TOSHIBA Photocoupler GaAlAs Ired & Photo IC

TLP559(IGM)

Transistor Inverters
Air Conditioner Inverters
Line Receivers
Intelligent Power Modules (IPMs) Interfaces

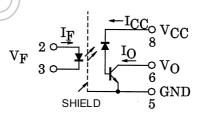
The TOSHIBA TLP559(IGM) consists of a high-output GaAlAs light emitting diode optically coupled to a high-speed photodiode with a transistor amplifier.

The TLP559(IGM) has no internal base connection. The Faraday shield in the photodetector chip provides an effective common-mode noise transient immunity.

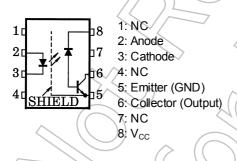
The TLP559(IGM) guarantees minimum and maximum propagation delay time, a relative time difference between the rise and fall time, and common-mode transient immunity. Therefore, the TLP559(IGM) is suitable for an isolation interface between an Intelligent Power Module (IPM) and a control IC in motor control applications.

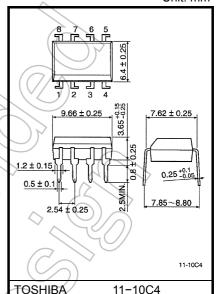
- Isolation Voltage: 2500 Vrms (min)
- Common-Mode Transient Immunity: ±10 kV/µs (min) @V_{CM} ≠ 1500 V
- Switching Time: t_{pHL} , t_{pLH} = 0.1µs (min), = 0.8µs (max) @J_F = 10 mA, V_{CC} = 15 V, R_L = 20 k Ω , Ta = 25°C
- Switching Time Dispersion: 0.7 μs (max) (|tpLH-tpHL|)
- TTL Compatible
- UL Recognized: UL1577, File No. E67349

Schematic



Pin Configuration (Top view)





Weight: 0.54 g (typ.)

Absolute Maximum Ratings (Ta = 25°C)

	CHARACTERISTIC		SYMBOL	RATING	UNIT
	Forward Current	(Note 1)	lF	25	mA
	Pulse Forward Current	(Note 2)	I _{FP}	50	mA
LED	Peak Transient Forward Current	(Note 3)	I _{FPT}	1	Α
	Reverse Voltage		V_{R}	5	V
	Diode Power Dissipation	(Note 4)	P_{D}	45	mW
	Output Current		Io /	8	mA
OR.	Peak Output Current		1 _{OP}	16	mA
DETECTOR	Output Voltage		Vø	-0.5 to 20	V
DET	Supply Voltage		Vcc	-0.5 to 30	V
	Output Power Dissipation	(Note 5)	Po	100	mW
Ope	rating Temperature Range	4	T _{opr}	-55 to 100	\°C
Stor	age Temperature Range		T _{stg}	-55 to 125	°C
Lead	d Solder Temperature(10s)	(Note 6)	T _{sol}	♦ 260	°C
Isola	ation Voltage(AC, 1 minute, R.H.≤60%, Ta=25°C)	(Note 7)	BVS	2500	Vrms

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

(Note 1) Derate 0.8 mA above 70°C.

(Note 2) 50% duty cycle, 1 ms pulse width. Derate 1.6 mA/°C above 70°C.

(Note 3) Pulse width PW ≤ 1µs, 300 pps.

(Note 4) Derate 0.9 mW/°C above 70°C.

(Note 5) Derate 2 mW/°C above 70°C.

(Note 6) Soldering portion of lead: up to 2mm from the body of the device.

(Note 7) Device considers a two-terminal device: pins 1, 2, 3 and 4 shorted together and

pins 5, 6, 7 and 8 shorted together.

Electrical Characteristics (Ta = 25°C)

CHARACTERISTIC		SYMBOL	TEST CONDITION	MIN	TYP.	MAX	UNIT
	Forward Voltage	V _F	I _F = 16 mA	_	1.65	1.85	V
(ED	Forward Voltage Temperature Coefficient	ΔV _F /ΔTa	I _F = 16 mA	_	-2	-	mV /°C
=	Reverse Current	I_{R}	V _R = 5 V	7	_	10	μΑ
	Capacitance between Terminal	CT	V = 0, f = 1 MHz	(-)	45	_	pF
	High Level Output Current	I _{OH} (1)	I _F = 0 mA, V _{CC} = V _O = 5.5 V		<i>)</i> 3	500	nA
~		I _{OH (2)}	I _F = 0 mA, V _{CC} = 30 V V _O = 20 V	<u>(</u>	_	5	
DETECTOR		Іон	I _F = 0 mA, V _{CC} = 30 V V _O = 20 V, Ta = 70°C)	ı	50	μA
DE.	High Level Supply Voltage	Icch	$I_F = 0 \text{ mA}, V_{CC} = 30 V$	_	0.01	1	μΑ
	Supply Voltage	V _{CC}	I _{CC} = 0.01 mA	30	4	\ \	V
	Output Voltage	Vo	I _O = 0.5 mA	20	///	_	V

Coupled Electrical Characteristics (Ta = 25°C)

CHARACTERISTIC	SYMBOL TEST CONDITION MIN TYP.	MAX UI	JNIT
Courset Transfer Datis	I _E = 10 mA, V _{CC} = 4.5 V V _O = 0.4 V	75	%
Current Transfer Ratio	I_{O} / I_{F} $I_{F} = 10 \text{ mA}, V_{CC} = 4.5 \text{ V}$ $V_{O} = 0.4 \text{ V}, Ta = -25 \text{ to } 100^{\circ}\text{C}$ 15 —	_	70
Low Level Output Voltage	VOL. I _F = 16 mA, V _{CC} = 4.5 V — — —	0.4	V

Isolation Characteristics (Ta = 25°C)

CHARACTERISTIC	SYMBOL	TEST CONDITION		MIN	TYP.	MAX	UNIT
Capacitance Input to Output	Cs	V = 0, f = 1 MHz (N	Note 7)	_	8.0	-	pF
Isolation Resistance	Rs	R.H. ≤ 60%, V _S = 500 V (N	Note 7)	5×10 ¹⁰	10 ¹⁴	_	Ω
		AC, 1 minute		2500		1	Vrma
Isolation Voltage	BVS	AC, 1 second, in oil		_	5000	_	Vrms
	4	DC, 1 minute, in oil		_	5000	_	Vdc

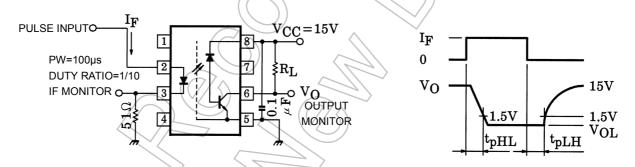
Switching Characteristics (Ta = 25°C, V_{CC} = 15 V)

CHARACTERISTIC	SYMBOL	TEST CIRCUIT	TEST CONDITION	MIN	TYP.	MAX	UNIT
			I_F = 10 mA, R_L = 20 kΩ	0.1	0.45	0.8	
Propagation Delay Time (H→L)	t _{pHL} t _{pLH}		I_F = 10 mA, R_L = 20 kΩ Ta = 0~85°C	0.1	0.45	0.9	μs
Propagation Delay Time (L→H)	φιπ	- 1	I_F = 10 mA, R_L = 20 kΩ Ta = -25~100°C	0.1	0.45	1.0	
	ltpLH-tpHLl		I _F = 10 mA, R _L = 20 kΩ		0.25	0.7	μs
Switching Time Dispersion between ON and OFF			I_F = 10 mA, R_L = 20 kΩ Ta = 0~85°C	()	0.25	0.8	
			I_F = 20 mA, R_L = 20 kΩ Ta = -25~100°C) —	0.25	0.9	
Common Mode Transient Immunity at Logic High Output (Note 8)	CM _H	2	$I_F = 0 \text{ mA},$ $V_{CM} = 1500 V_{p-p},$ $R_L = 20 \text{ k}\Omega$	10000	15000	<u> </u> />	V /µs
Common Mode Transient Immunity at Logic Low Output (Note 8)	CML	2	$I_F = 10 \text{ mA},$ $V_{CM} = 1500 \text{ V}_{p+p},$ $R_L = 20 \text{ k}\Omega$	-10000	-15000	> _	V /µs

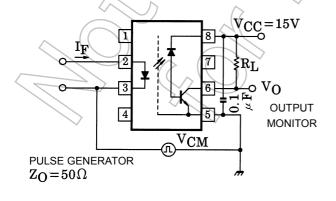
(Note 8) CM_L is the maximum rate of fall of the common mode voltage that can be sustained with the output voltage in the logic low state(Vo<1V).</p>
CM_H is the maximum rate of rise of the common mode voltage that can be sustained with the output voltage in the logic high state(Vo>4V).

(Note 9) Maximum electrostatic discharge voltage for any pins: 100V(C ≤ 200pF, R=0)

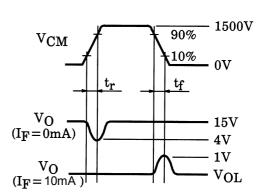
Test Circuit 1: Switching time test circuit



Test Circuit 2: Common mode noise immunity test circuit



$${\rm CM}_{H} = \frac{1200(V)}{{\rm t}_{\rm r}(\mu {\rm s})} \,, \ \, {\rm CM}_{L} = \frac{1200(V)}{{\rm t}_{\rm f}(\mu {\rm s})} \,$$



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